	Application No.	Applicant(s)
Notice of Allowability	10/765,276	TAKEOKA ET AL.
	Examiner	Art Unit
	Vuthe Siek	2825
	1	<u> </u>
The MAILING DATE of this communication appeal All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIOF the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this app or other appropriate communication IGHTS. This application is subject to	olication. If not included will be mailed in due course. THIS
1. \boxtimes This communication is responsive to <u>communication filed of</u>	on 6/27/07.	
2. X The allowed claim(s) is/are 3-14,16,18 and 20-23.	•	
3. ☐ Acknowledgment is made of a claim for foreign priority ur a) ☐ All b) ☐ Some* c) ☐ None of the:		
1. Certified copies of the priority documents have been received.		
2. Certified copies of the priority documents have been received in Application No		
3. Copies of the certified copies of the priority documents have been received in this national stage application from the		
International Bureau (PCT Rule 17.2(a)).		
* Certified copies not received:		•
Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application. THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		
 A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give 		
5. CORRECTED DRAWINGS (as "replacement sheets") mus	st be submitted.	
(a) ☐ including changes required by the Notice of Draftspers	son's Patent Drawing Review (PTO-	948) attached
1) 🔲 hereto or 2) 🔲 to Paper No./Mail Date	:	
(b) ☐ including changes required by the attached Examiner's Paper No./Mail Date	s Amendment / Comment or in the C	Office action of
Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in t		
 DEPOSIT OF and/or INFORMATION about the depo attached Examiner's comment regarding REQUIREMENT 	SIT OF BIOLOGICAL MATERIAL IN FOR THE DEPOSIT OF BIOLOGICA	nust be submitted. Note the AL MATERIAL.
Attachment(s)		
1. Notice of References Cited (PTO-892)	5. Notice of Informal P	•
2. Notice of Draftperson's Patent Drawing Review (PTO-948)	 Interview Summary Paper No./Mail Dat 	e:
 Information Disclosure Statements (PTO/SB/08), Paper No./Mail Date 	7. Examiner's Amendn	
Examiner's Comment Regarding Requirement for Deposit of Biological Material	* 8. ⊠ Examiner's Stateme 9. □ Other	ent of Reasons for Allowance
·	- <u> </u>	
		/Vuthe Siek/ Vuthe Siek Primary Examiner, A.U. 2825

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DETAILED ACTION

1. This office action is in response to application 10/765,276 and amendment filed on 6/27/2007. Claims 3-14, 16, 18 and 20-23 remain pending in the application, where claims 1-2, 15, 17 and 19 are canceled. Note that the request to rejoin claims 18 and 20 has been accepted.

Examiner's Amendment

2. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

The status of claim 18 and 20 has changed as follows:

Claim 18 (Previously Presented).

Claim 20 (Previously Presented).

The changes correct the status of the claims according to rejoin claims 18 and 20 to claim 3.

EXAMINER'S STATEMENT AS TO THE REASONS FOR ALLOWANCE

- 3. Claims 3-14, 16, 18 and 20-23 are allowed over the prior art of record.
- 4. The following is an examiner's statement of reasons for allowance: the prior art of record does not teach or fairly suggest a method of evaluating the quality of test sequences for delay faults comprising each of defined delay faults which are delay faults existed in a semiconductor integrated circuit is assigned a predetermined delay value; and the result of the total of the delay values of the "delay faults detected by the

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test sequences for delay values" divided by the predetermined delay values of the defined delay faults is set as a fault coverage and evaluating the quality of the "test sequences for delay faults" based on the fault coverage.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Vuthe Siek whose telephone number is (571) 272-1906. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Jack Chiang can be reached on (571) 272-7483. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

/Vuthe Siek/ Vuthe Siek Primary Examiner, A.U. 2825